

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/757,274	MAEDA, PATRICK Y.	
Examiner	Art Unit	

2861

Hai C. Pham

	SEARCHED				
Class	Subclass	Date	Examiner		
347	130, 134,238, 241-244, 256-258	2/4/2006	HP		
372	45	2/4/2006	HP		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST Text Search	2/4/2006	НР	